

The workshop is designed to support the use of XPS and related techniques by students and research scientists. Material presented in the workshop has developed as a consequence of interactions with many universities. In particular University of Nantes organised a CNRS Thematic Workshop in Roscoff 2013 which demonstrated the potential of these events.

- The duration for the workshop will be six hours on the day before ECASIA 2015, presented by Neal Fairley the creator of CasaXPS.
- The training course will introduce new features to CasaXPS developed for the release version 2.3.17.
- These new features and existing functionality in CasaXPS will be presented as a sequence of lecture sessions followed by hands-on workshop sessions.
- Workshop sessions will be based on videos and data.
- These videos are provided to permit subjects covered in the lecture periods to be explored using data introduced in lectures.
- Workshop material will be available at multiple levels so individuals can choose to explore CasaXPS 2.3.17 at an appropriate level for their current knowledge, with technical support available to answer questions and provide guidance when necessary.

Laptops will be required by those wishing to participate in the workshop sessions. CasaXPS 2.3.17, videos and data will be provided for transfer to personal laptops.

Principal XPS Data Set used in Workshop

Experimental data leading to the paper by Beamson *et al* will be used throughout the course to illustrate features in CasaXPS 2.3.17.

Composition depth profiling of polystyrene/poly(vinyl ethyl ether) blend thin films by angle resolved XPS,

Journal of Electron Spectroscopy and Related Phenomena 171 (2009) 57–63. G. Beamson, P. Mokarian-Tabari, M. Geoghegan

Data treatment techniques are further developed using data sets measured from molybdenum and copper oxides. Again these data sets were designed to include evolving spectral shapes. Interim results from these data were presented in poster format at AVS 2013.

Generalized molybdenum oxide surface chemical state XPS determination via informed amorphous sample model,

Applied Surface Science Volume 326, 30 January 2015, Pages 151–161 J. Baltrusaitis, B. Mendoza-Sanchez, V. Fernandez, R. Veenstra, N. Dukstiene, A. Roberts, N. Fairley



The book to accompany the workshop developed as a result of Roscoff 2013.